

EXPRESS MAIL NO.: EV 415954305 US
IN THE U.S. PATENT AND TRADEMARK OFFICE

In re U.S. Patent Application of:

APPLICANT: Xiao, et al.
SERIAL NO.: Not yet assigned
FILING DATE: Herewith
EXAMINER: Not yet assigned
ART UNIT: Not yet assigned
DOCKET NO.: 904.0101.U2(US)
TITLE: **REDUCTION OF NOISE, AND OPTIMIZATION OF
MAGNETIC FIELD SENSITIVITY AND ELECTRICAL
PROPERTIES IN MAGNETIC TUNNEL JUNCTION DEVICES**

MAIL STOP: PATENT APPLICATION

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450


INFORMATION DISCLOSURE STATEMENT (37 C.F.R. 1.98(d))

Dear Sir:

Pursuant to Sections 609 and 707.05(b) of the MPEP and 37 CFR 1.97-1.99, this IDS makes of record the prior art that was cited in the parent application **S.N. 10/105,831**, filed on **March 25, 2002**, which is relied on for an earlier filing date by the present patent application. The attached pages of PTO-1449 list the prior art from the parent application and other references. Since this application relies on the parent application for an earlier filing date, copies of the references cited in that parent application are not enclosed (37 C.F.R. 1.98(d)). However, if for any reason these references are not be found in the file jacket of the parent application, the Examiner is respectfully requested to contact the undersigned attorney, who will gladly provide copies of any missing references.

The citation of these documents should not be construed as a representation that a thorough search has been made, or that other, more pertinent material is not available.

Respectfully submitted,


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April 14, 2004

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**INFORMATION DISCLOSURE
CITATION FORM FOR
PATENT APPLICATION
(FORM PTO-1449)
(Substitute)**

Docket No.: 904.0101.U2(US)

Serial No.

Applicant(s): Xiao et al.

Filing Date: herewith

Group: 2818

U.S. PATENT DOCUMENTS

Examiner Initials	Document Number (Number-Kind Code)	Publication Date (MM-DD-YYYY)	Name of Patentee or Applicant	Class	Sub-class
	US-6,448,766 B1	09-10-2002	Berger et al.	324	244
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Examiner Initials	Document Number (Country Code-Number-Kind Code)	Publication Date (MM-DD-YYYY)	Name Of Patentee of Applicant	Translation? Yes/No/n/a
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OTHER DOCUMENTS (Author (Capitalize), Title, Date, Pages, Etc., if known)

	B.L.T. Plourde et al., "Design of a Scanning Josephson Junction Microscope for Submicron-Resolution Magnetic Imaging", Review of Scientific Instruments, Vol. 70, No. 11, pp 4344-4347, November 1999.
	S. Y. Yamamoto et al., "Scanning magnetoresistance microscopy", Appl. Phys. Lett. Vol. 69, No. 21, November 18, 1996, pp. 3263-3265
	Michael K. Ho, et al., "Study of Magnetic Tunnel Junction Read Sensors", IEEE Transactions on Magnetics, Vol. 37, No. 4, July 2001, pp. 1691-1694
	Jian-Qing-Wang et al., "Large finite-size effect of giant magnetoresistance in magnetic granular thin films", Inst. Of Electrical Engineers, Stevenage, UK, 1995, 2 pages

Examiner's Signature:

Date Considered:

Initial if reference was considered, whether or not citation is in conformance with MPEP. Mark through citation if not considered.
Include a copy of this citation form with your next correspondence to the Applicant(s).

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	S. Ingvarsson et al., "Electronic noise in magnetic tunnel junctions", Journal of Applied Physics, vol. 85, page 5270, 1999.
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	E.R. Nowalk, et al., "Noise properties of ferromagnetic tunnel junctions", Journal of Applied Physics, Vol. 84, page 6195, 1998.
	D.S. Reed, "Low frequency noise in magnetic tunnel junctions", IEEE Transactions on Magnetics, vol. 37, page 2028, 2001.

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